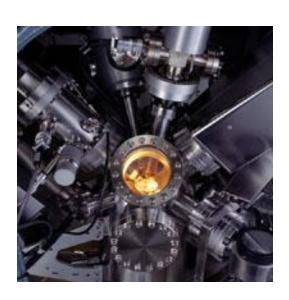
CHE680 Advanced Analytical Chemistry Lecture 6

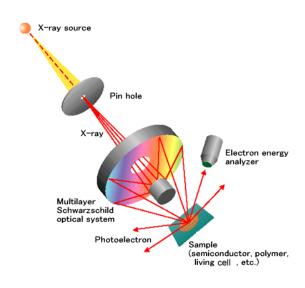


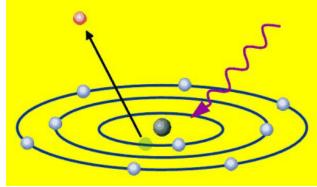
Jamie Kim
Department of Chemistry
Buffalo State College

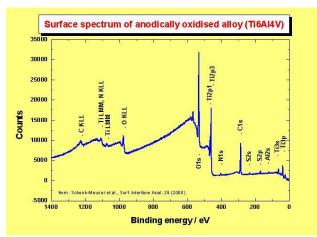
- 1. Basic Principles
- 2. Experimental Condition
- 3. Generation of X-rays
- 4. Detectors
- 5. Applications

X-ray Photoelectron Spectroscopy (XPS)









X-ray Photoelectron Spectroscopy (XPS)

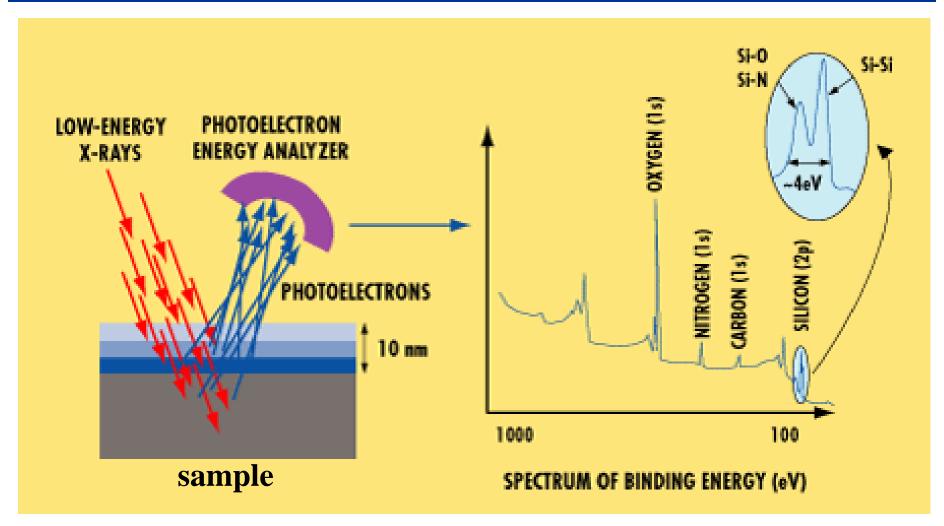
XPS also referred to as *Electron Spectroscopy for Chemical Analysis* (*ESCA*), identifies elements by analyzing energies of photoelectrons ejected by monochromatic X-rays.

The energy of each photoelectron is directly related to the atom from which it was removed; therefore *identifying elements on a sample surface* is possible.

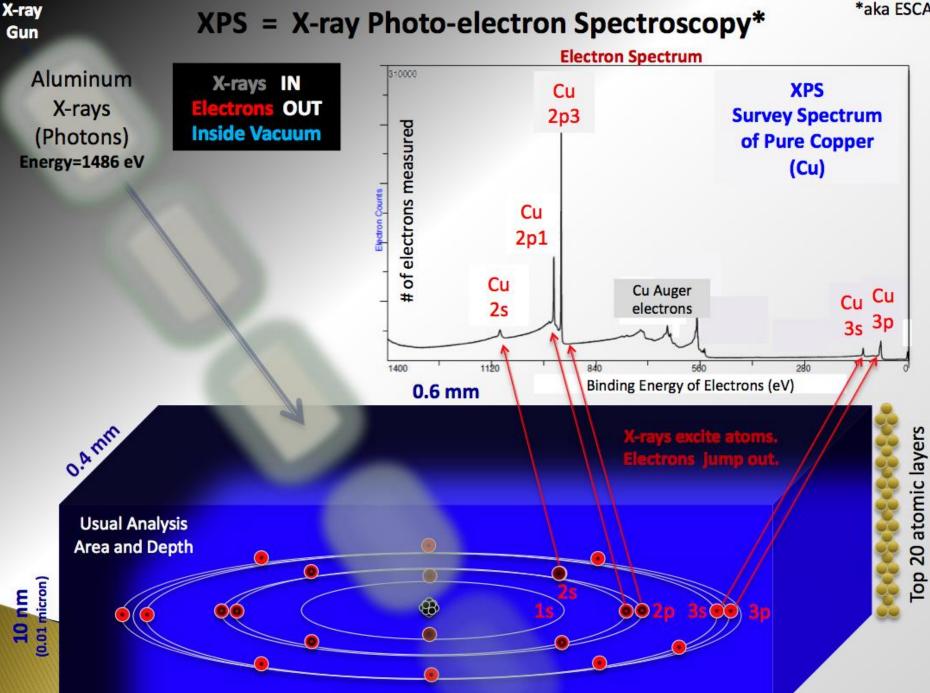
A high-resolution spectrometer sums the number of ejected photoelectrons at specific levels of energy, and these sums are converted into elemental compositions.

In many cases, valence state(s) or chemical bonding environment(s) are also identifiable from these sums.

Overview of XPS



qualitative (peak positions) and quantitative (peak intensities) surface analysis



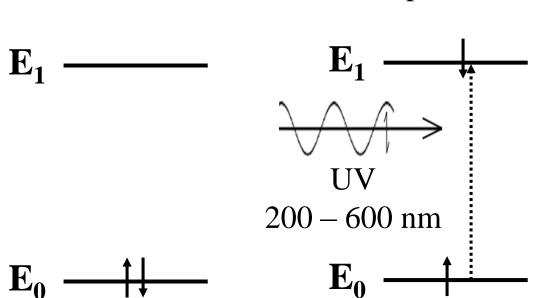
XPS vs. UV/Vis: What's the Extreme Electronic Transition?

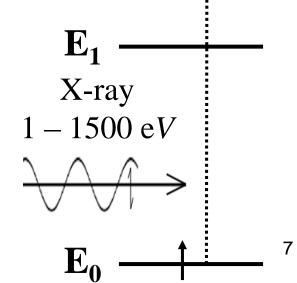
$$1.0 \ eV = 1240 \ \text{nm}$$

 $200 - 600 \ \text{nm} = 6 - 2 \ eV$

measure KE
of ejected electrons.

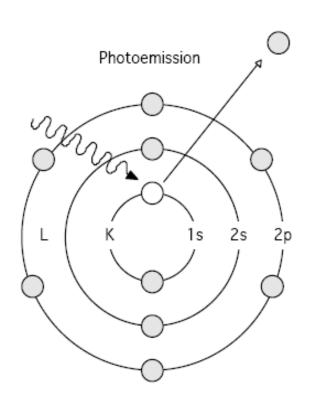
measure UV absorption for $\sim \Delta E$

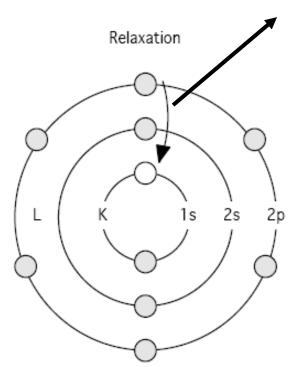


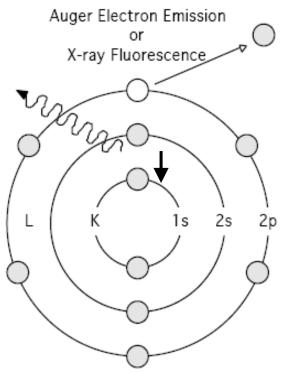


Fate of Core Holes

X-ray generation

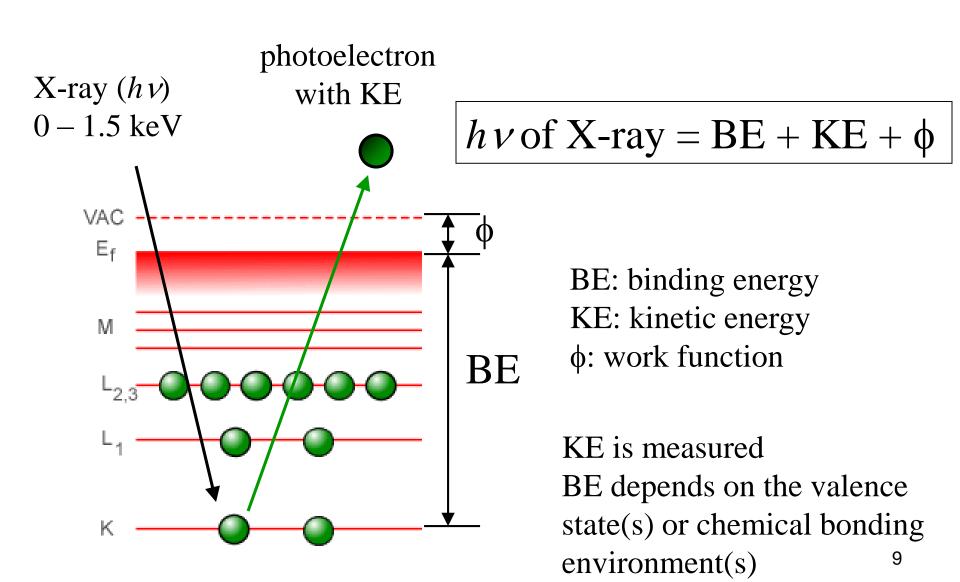




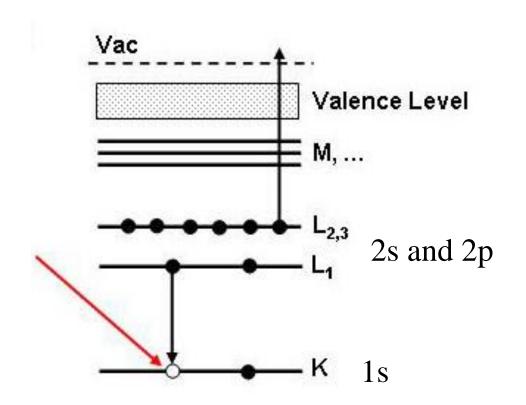


Auger electron spectroscopy

Principles of (XPS)



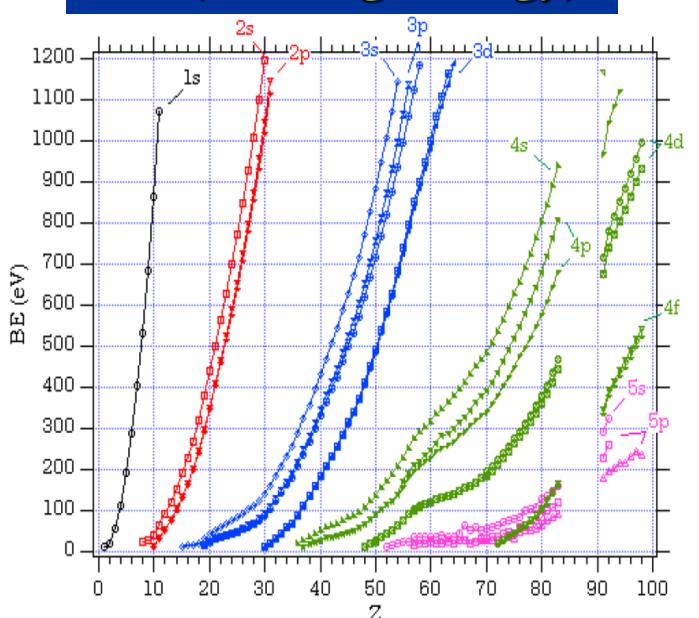
Auger Electron Spectroscopy (AES)



$$KL_1L_{2,3}$$
 transition
= (KLL)

- 1. An electron in K shell (1s orbital) is removed by x-ray.
- 2. For a $KL_1L_{2,3}$ transition, K (the core level hole,) L_1 (the relaxing electron's initial state), and $L_{2,3}$ (the emitted electron's initial energy state).
- 3. Similarly, there are LMM, MNN types of transitions in an Auger spectra.

BE (Binding Energy)

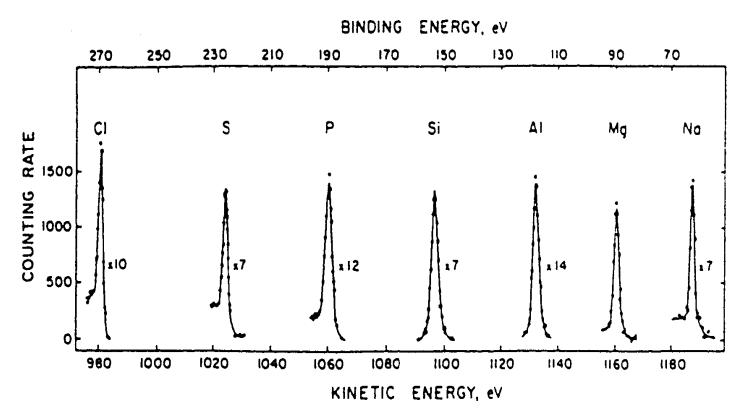


BE (Binding Energy)

Energy of levels:

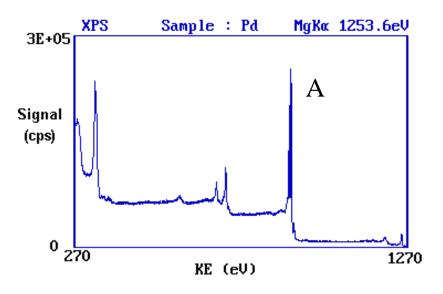
Atomic number (Z):

 $BE(Na\ 1s) \le BE(Mg\ 1s) \le BE(Al\ 1s)...$



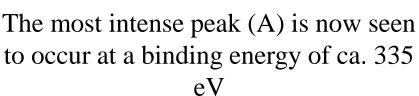
How Does It Work?

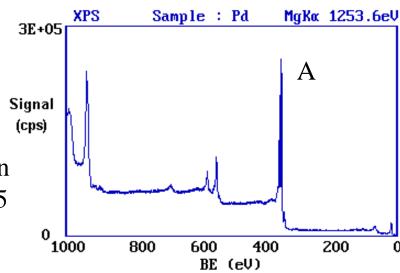
XPS spectrum from a Pd metal sample using Mg K_{α} radiation



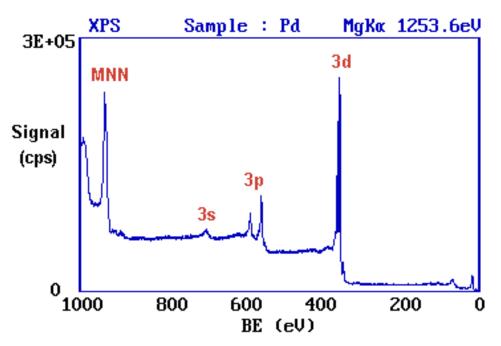
the main peaks occur at kinetic energies of ca. 330, 690, 720, 910 and 920 eV.

Plotting against BE as opposed to KE.





Chemical and Structural Information

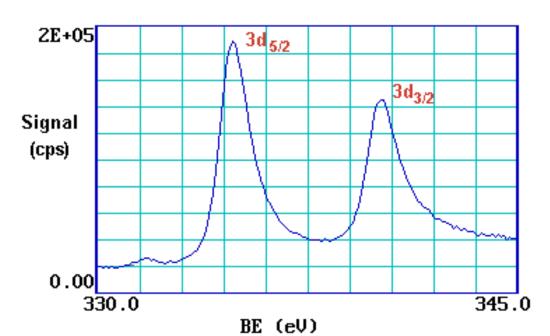


- 1. the valence band (4*d*,5*s*) emission occurs: ca. 0 8 eV (measured with respect to the Fermi level, or alternatively at ca. 4 12 eV if measured with respect to the vacuum level).
- 2. the 4*p* and 4*s*: 54 and 88 eV, respectively
- 3. the 3d/sp/3s: ca. 335, ca. 534/561, and 673 eV respectively.
- 4. the remaining peak is not an XPS peak at all ! it is an Auger peak arising from x-ray induced *Auger emission*. It occurs at a kinetic energy of ca. 330 eV.

Complexity of XPS Spectra I: Spin-Orbit Splitting

Closer inspection of the spectrum shows that emission from some levels (most obviously 3p and 3d) produces a closely spaced doublet. Why?

For d electron in d^9 system, 1–s coupling produces j = 5/2 and 3/2 (for d electron, l = 2 and $s = \frac{1}{2}$, $j = l + s \dots l - s$).

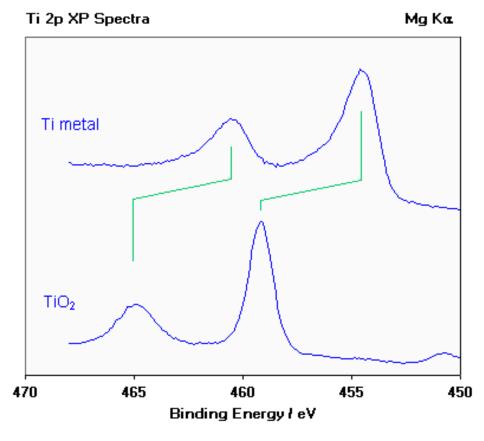


Complexity of XPS Spectra II: Chemical Shift

The exact binding energy of an electron also depends on:

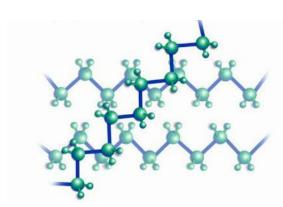
- 1. the formal oxidation state of the atom
- 2. the local chemical and physical environment

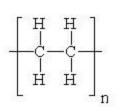
Changes in either (1) or (2) give rise to small shifts in the peak positions in the spectrum - so-called *chemical shifts*.



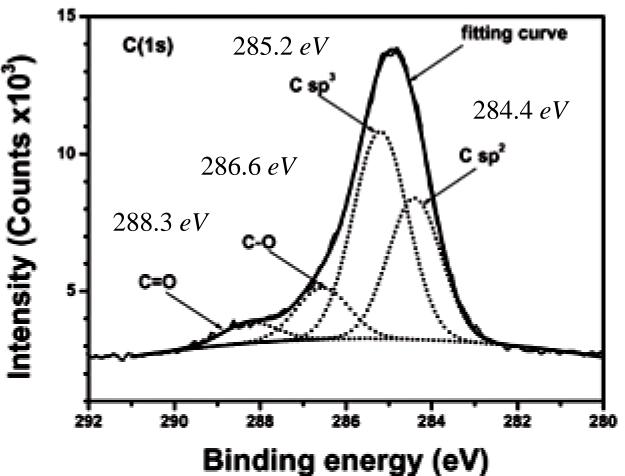
Actual XPS Peak Analysis by Fitting



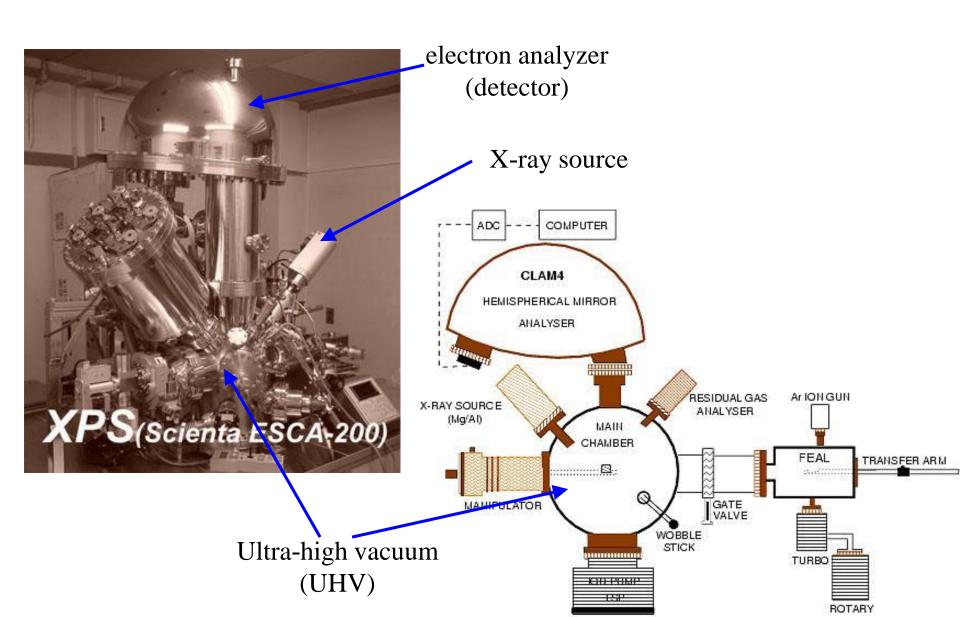




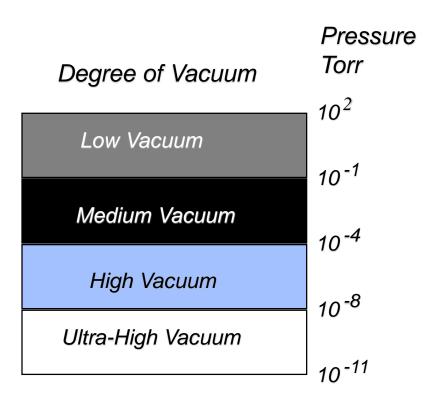
XPS spectrun of carbon atoms in ultrahigh molecular weight polyethylene (UHMWPE) after surface oxidation



Instrumentation



Why UHV for Surface Analysis?



- ☐ Remove adsorbed gases from the sample.
- Eliminate adsorption of contaminants on the sample.
- Prevent arcing and high voltage breakdown.
- ☐ Increase the mean free path for electrons, ions and photons.

X-ray Source

The most commonly employed x-ray sources are those giving rise to:

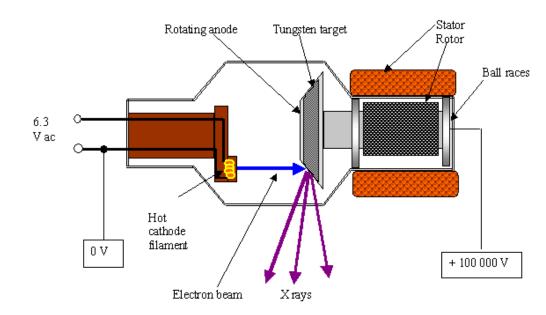
Mg K_{α} radiation : hv = 1253.6 eV

Al K_{α} radiation : hv = 1486.6 eV

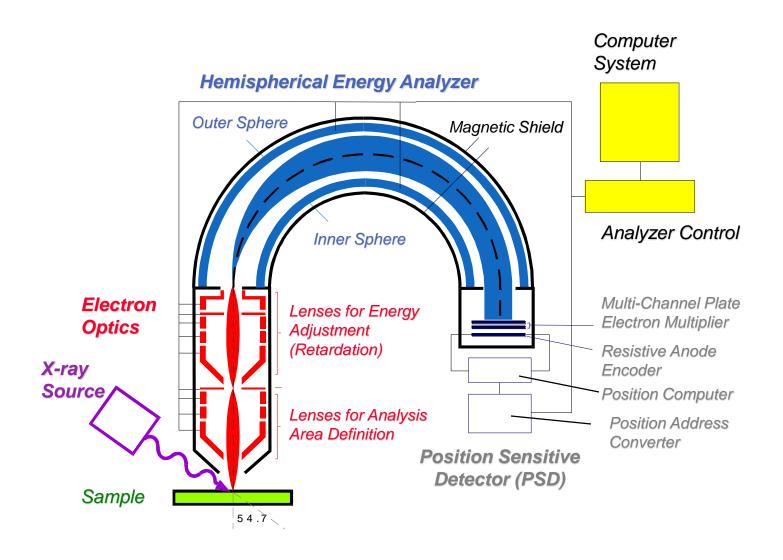
$$eV = \frac{1}{2}mv^2 = hv_{\text{max}}$$

Twin Anode X-Ray Source for XPS



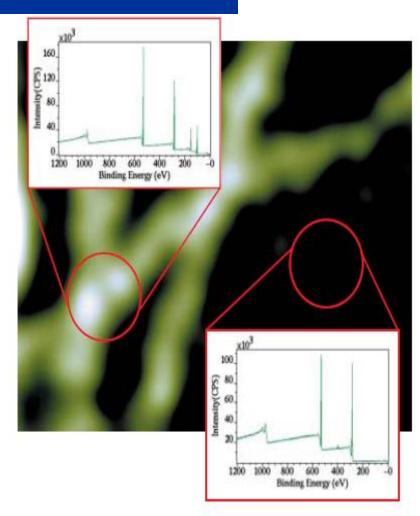


Detector: Electron Analyzer



Applications of XPS

- Characterization of reactive interactions at interfaces
- Analysis of concentrations of chemical substances at interfaces
- Detection of impurities on material surfaces (failure analysis)
- Studying gas-solid reactions at surfaces (catalysis)
- Investigation of solid-solid reactions when there is reactive frictional wear
- Analysis of surface pretreatment/treatment, e.g. using plasma techniques

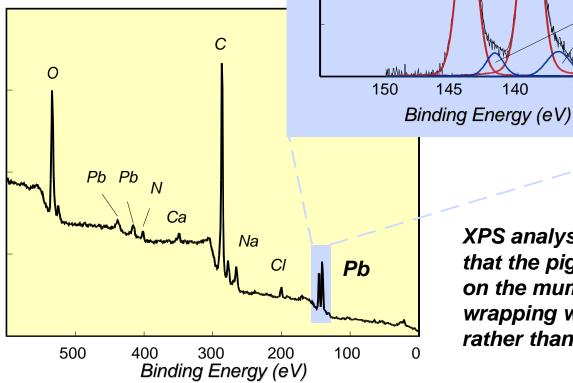


Silicon distribution in silicone-coated polyamide fibres (\emptyset = 12 μ m) on a pressure sensitive adhesive tape (Section: 350x350 μ m)

XPS Analysis of Pigment from Mummy Artwork



Egyptian Mummy 2nd Century AD World Heritage Museum University of Illinois



XPS analysis showed that the pigment used on the mummy wrapping was Pb₃O₄ rather than Fe₂O_{3 23}

 PbO_2

135

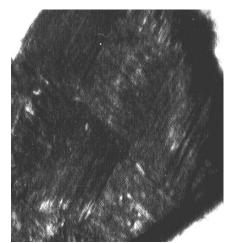
130

140

 Pb_3O_4

Analysis of Carbon Fiber- Polymer Composite Material by XPS





Woven carbon fiber composite

XPS analysis identifies the functional groups present on composite surface. Chemical nature of fiber-polymer interface will influence its properties.

